

MOS INTEGRATED CIRCUIT μ PD43256B

256K-BIT CMOS STATIC RAM 32K-WORD BY 8-BIT

Description

The µPD43256B is a high speed, low power, and 262,144 bits (32,768 words by 8 bits) CMOS static RAM.

Battery backup is available. And A and B versions are wide voltage operations.

The µPD43256B is packed in 28-pin PLASTIC DIP, 28-pin PLASTIC SOP and 28-pin PLASTIC TSOP (I) (8 x 13.4 mm).

Features

- 32,768 words by 8 bits organization
- Fast access time: 70, 85, 100, 120, 150 ns (MAX.)
- Low voltage operation (A version: Vcc = 3.0 to 5.5 V, B version: Vcc = 2.7 to 5.5 V)
- Low Vcc data retention: 2.0 V (MIN.)
- /OE input for easy application

Part number	Access time	Operating supply	Operating ambient	Supply current		
	ns (MAX.)	voltage	temperature	At operating	At standby	At data retention
		V	°C	mA (MAX.)	μΑ (MAX.)	$\mu A (MAX.)^{Note1}$
μPD43256B-xxL	70, 85	4.5 to 5.5	0 to 70	45	50	3
μPD43256B-xxLL					15	2
μPD43256B-Axx	85, 100 ^{Note2} , 120 ^{Note2}	3.0 to 5.5				
µPD43256B-Bxx ^{№ote2}	100, 120, 150	2.7 to 5.5				

Notes 1. TA \leq 40 °C, Vcc = 3.0 V

2. Access time: 85 ns (MAX.) (Vcc = 4.5 to 5.5 V)

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Ordering Information

(1/	2)
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Part number	Package	Access time ns (MAX.)	Operating supply voltage	Operating ambient temperature	Remark
			V	C	
μPD43256BCZ-70L	28-pin PLASTIC DIP	70	4.5 to 5.5	0 to 70	L version
μPD43256BCZ-85L	(15.24 mm (600))	85			
μPD43256BCZ-70LL	-	70			LL version
μPD43256BCZ-85LL		85			
μPD43256BGU-70L	28-pin PLASTIC SOP	70			L version
μPD43256BGU-85L	(11.43 mm (450))	85			
μPD43256BGU-70LL		70			LL version
μPD43256BGU-85LL		85			
μPD43256BGU-A85		85	3.0 to 5.5		A version
μPD43256BGU-A10		100			
μPD43256BGU-A12		120			
μPD43256BGU-B10		100	2.7 to 5.5		B version
μPD43256BGU-B12		120			
μPD43256BGW-70LL-9JL	28-pin PLASTIC TSOP (I)	70	4.5 to 5.5		LL version
μPD43256BGW-85LL-9JL	(8x13.4) (Normal bent)	85			
μPD43256BGW-A85-9JL		85	3.0 to 5.5		A version
μPD43256BGW-A10-9JL		100			
μPD43256BGW-A12-9JL		120			
μPD43256BGW-B10-9JL		100	2.7 to 5.5		B version
μPD43256BGW-B12-9JL		120			
μPD43256BGW-B15-9JL		150			
μPD43256BGW-70LL-9KL	28-pin PLASTIC TSOP (I)	70	4.5 to 5.5		LL version
μPD43256BGW-85LL-9KL	(8x13.4) (Reverse bent)	85			
μPD43256BGW-A85-9KL		85	3.0 to 5.5		A version
μPD43256BGW-A10-9KL		100			
μPD43256BGW-A12-9KL	1	120			
μPD43256BGW-B10-9KL		100	2.7 to 5.5		B version
μPD43256BGW-B12-9KL		120			
μPD43256BGW-B15-9KL		150			

Part number	Package	Access time	Operating supply	Operating ambient	Remark
		ns (MAX.)	voltage	temperature	
			V	°C	
μPD43256BGU-70L-A	28-pin PLASTIC SOP	70	4.5 to 5.5	0 to 70	L version
μPD43256BGU-85L-A	(11.43 mm (450))	85			
μPD43256BGU-70LL-A		70			LL version
μPD43256BGU-85LL-A		85			
μPD43256BGU-A85-A		85	3.0 to 5.5		A version
μPD43256BGU-A10-A		100			
μPD43256BGU-A12-A		120			
μPD43256BGU-B10-A		100	2.7 to 5.5		B version
μPD43256BGU-B12-A		120			
μPD43256BGW-70LL-9JL-A	28-pin PLASTIC TSOP (I)	70	4.5 to 5.5		LL version
μPD43256BGW-85LL-9JL-A	(8x13.4) (Normal bent)	85			
μPD43256BGW-A85-9JL-A		85	3.0 to 5.5		A version
μPD43256BGW-A10-9JL-A		100			
μPD43256BGW-A12-9JL-A		120			
μPD43256BGW-B10-9JL-A		100	2.7 to 5.5		B version
μPD43256BGW-B12-9JL-A		120			
μPD43256BGW-B15-9JL-A		150			
μPD43256BGW-70LL-9KL-A	28-pin PLASTIC TSOP (I)	70	4.5 to 5.5		LL version
μPD43256BGW-85LL-9KL-A	(8x13.4) (Reverse bent)	85			
μPD43256BGW-A85-9KL-A		85	3.0 to 5.5		A version
μPD43256BGW-A10-9KL-A		100			
μPD43256BGW-A12-9KL-A		120			
μPD43256BGW-B10-9KL-A]	100	2.7 to 5.5		B version
μPD43256BGW-B12-9KL-A		120			
μPD43256BGW-B15-9KL-A		150			

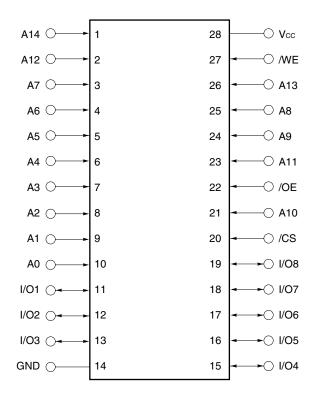
(2/2)

Remark Products with -A at the end of the part number are lead-free products.

Pin Configurations (Marking Side)

/xxx indicates active low signal.

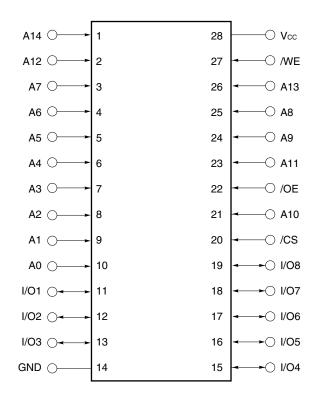




A0 - A14	: Address inputs
I/O1 - I/O8	: Data inputs / outputs
/CS	: Chip Select
/WE	: Write Enable
/OE	: Output Enable
Vcc	: Power supply
GND	: Ground

Remark Refer to Package Drawings for the 1-pin index mark.

- 28-pin PLASTIC SOP (11.43 mm (450))
 - [*µ*PD43256BGU-xxL]
 - [*µ*PD43256BGU-xxLL]
 - [*µ*PD43256BGU-Axx]
 - [*µ*PD43256BGU-Bxx]
 - [*µ*PD43256BGU-xxL-A]
 - [μPD43256BGU-xxLL-A] [μPD43256BGU-Axx-A]
 - [*µ*PD43256BGU-Bxx-A]

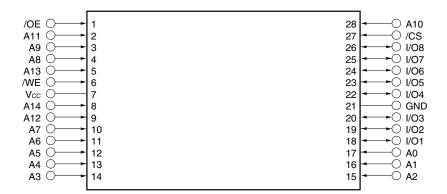


A0 - A14	: Address inputs
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Remark Refer to Package Drawings for the 1-pin index mark.

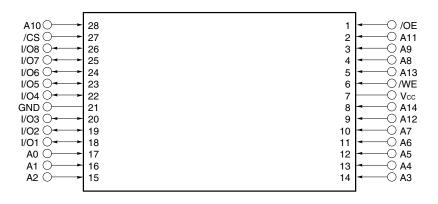
28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)

- [*µ*PD43256BGW-xxLL-9JL]
- [*µ*PD43256BGW-Axx-9JL]
- [*µ*PD43256BGW-Bxx-9JL]
- [*µ*PD43256BGW-xxLL-9JL-A]
- [*µ*PD43256BGW-Axx-9JL-A]
- [*µ*PD43256BGW-Bxx-9JL-A]



28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)

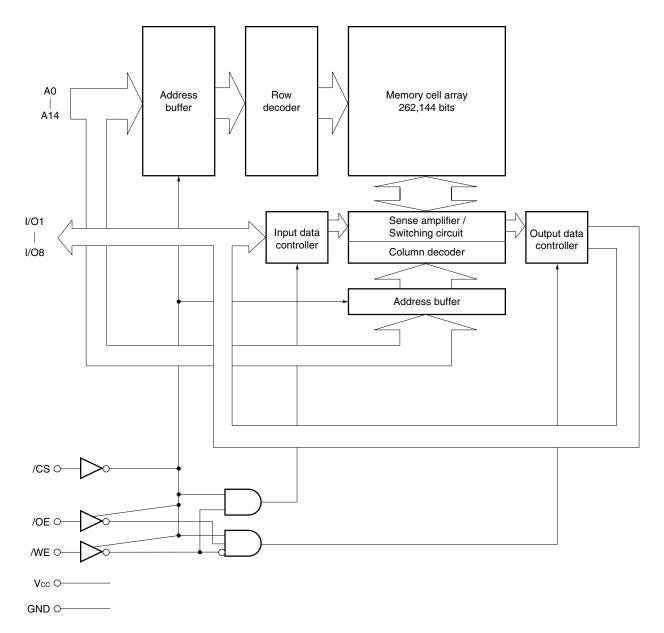
- [*µ*PD43256BGW-xxLL-9KL]
- [*µ*PD43256BGW-Axx-9KL]
- [*µ*PD43256BGW-Bxx-9KL]
- [*µ*PD43256BGW-xxLL-9KL-A]
- [*µ*PD43256BGW-Axx-9KL-A]
- [*µ*PD43256BGW-Bxx-9KL-A]



A0 - A14	:	Address inputs	/OE	:	Output Enable
I/O1 - I/O8	:	Data inputs / outputs	Vcc	:	Power supply
/CS	:	Chip Select	GND	:	Ground
/WE	:	Write Enable			

Remark Refer to **Package Drawings** for the 1-pin index mark.

Block Diagram



Truth Table

/CS	/OE	/WE	Mode	I/O	Supply current
Н	×	×	Not selected	High impedance	lsв
L	Н	Н	Output disable		ICCA
L	×	L	Write	Ли	
L	L	Н	Read	Dout	

Remark ×: VIH or VIL

Electrical Specifications

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Supply voltage	Vcc		-0.5 ^{Note} to +7.0	V
Input / Output voltage	VT		-0.5 ^{Note} to Vcc + 0.5	V
Operating ambient temperature	TA		0 to 70	°C
Storage temperature	Tstg		-55 to +125	°C

Note -3.0 V (MIN.) (Pulse width : 50 ns)

Caution Exposing the device to stress above those listed in Absolute Maximum Rating could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	μPD43256B-xxL		μPD43256B-Axx		μPD43256B-Bxx		Unit
			μPD43256B-xxLL						
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Supply voltage	Vcc		4.5	5.5	3.0	5.5	2.7	5.5	V
High level input voltage	VIH		2.2	Vcc+0.5	2.2	Vcc+0.5	2.2	Vcc+0.5	V
Low level input voltage	V∟		-0.3 ^{Note}	+0.8	-0.3 Note	+0.5	-0.3 ^{Note}	+0.5	V
Operating ambient temperature	TA		0	70	0	70	0	70	°C

Note -3.0 V (MIN.) (Pulse width: 50 ns)

Capacitance (T_A = 25 °C, f = 1 MHz)

Parameter	Symbol	Test conditions	MIN.	TYP.	MAX.	Unit
Input capacitance	Cin	$V_{IN} = 0 V$			5	pF
Input / Output capacitance	Cı/o	$V_{I/O} = 0 V$			8	pF

Remarks 1. VIN : Input voltage

VI/0 : Input / Output voltage

2. These parameters are periodically sampled and not 100% tested.

Parameter	Symbol	Test condition	μPD43256B-xxL		μPD	Unit			
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Input leakage current	lu	$V_{IN} = 0 V \text{ to } V_{CC}$	-1.0		+1.0	-1.0		+1.0	μA
I/O leakage current	Ilo	$V_{I/O} = 0 V$ to V_{CC} , $/OE = V_{IH}$ or	-1.0		+1.0	-1.0		+1.0	μA
		$/CS = V_{IH} \text{ or } /WE = V_{IL}$							
Operating supply current	ICCA1	/CS = V _{IL} , Minimum cycle time, $I_{I/O} = 0$ mA			45			45	mA
	ICCA2	/CS = VIL, II/0 = 0 mA			10			10	
	Іссаз	/CS \leq 0.2 V, Cycle = 1 MHz,			10			10	
		$I_{\text{I/O}}$ = 0 mA, V_{IL} \leq 0.2 V, V_{IH} \geq V_{CC} $-$ 0.2 V							
Standby supply current	lsв	/CS = VIH			3			3	mA
	ISB1	$/CS \ge V_{CC} - 0.2 V$		1.0	50		0.5	15	μA
High level output voltage	V _{OH1}	Iон = -1.0 mA	2.4			2.4			v
	Vон2	Іон = -0.1 mA	Vcc-0.5			Vcc-0.5			
Low level output voltage	Vol	lo∟ = 2.1 mA			0.4			0.4	V

DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted) (1/2)

Remarks 1. VIN : Input voltage

Vi/o : Input / Output voltage

2. These DC characteristics are in common regardless of package types.

Parameter	Symbol	Test condit	ion		μPD	43256B	-Axx	μPD43256B-Bxx			Unit
					MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Input leakage current	lu	V _{IN} = 0 V to V _{CC}			-1.0		+1.0	-1.0		+1.0	μA
I/O leakage current	Ilo	$V_{I/O} = 0 V$ to V_{CC} , $/OE = V_{IR}$	H Or		-1.0		+1.0	-1.0		+1.0	μA
		$/CS = V_{IH} \text{ or } /WE = V_{IL}$	1								
Operating supply current	ICCA1	$/CS = V_{IL},$	μPD	43256B-Axx			45			-	mA
		Minimum cycle time,	μPD	43256B-Bxx			-			45	
		Ivo = 0 mA		$Vcc \le 3.3 V$			-			20	
	ICCA2	/CS = VIL, I⊮o = 0 mA					10			10	
				$V_{CC} \le 3.3 V$			-			5	
	Іссаз	/CS \leq 0.2 V, Cycle = 1 MH	$/CS \le 0.2$ V, Cycle = 1 MHz, I $_{VO}$ = 0 mA,				10			10	
		$V_{\text{IL}} \leq 0.2 \text{ V}, \text{ V}_{\text{IH}} \geq V_{\text{CC}} - 0.2$	2 V	$V_{CC} \leq 3.3 V$			-			5	
Standby supply current	lsв	/CS = V⊮					3			3	mA
				$V_{CC} \le 3.3 V$			_			2	
	ISB1	$/CS \ge V_{CC} - 0.2 V$				0.5	15		0.5	15	μA
				$V_{CC} \le 3.3 V$			-		0.5	10	
High level output voltage	V _{OH1}	Іон = -1.0 mA, Vcc ≥ 4.5 V	'		2.4			2.4			v
		Іон = –0.5 mA, Vcc < 4.5 V		2.4			2.4				
	V _{OH2}	Іон = -0.02 mA			Vcc-0.1			Vcc-0.1			
Low level output voltage	Vol	lo∟ = 2.1 mA, Vcc ≥ 4.5 V				0.4			0.4	v	
		IoL = 1.0 mA, Vcc < 4.5 V	lo∟ = 1.0 mA, Vcc < 4.5 V				0.4			0.4	
	Vol1	loL = 0.02 mA					0.1			0.1	

DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted) (2/2)

Remarks 1. VIN : Input voltage

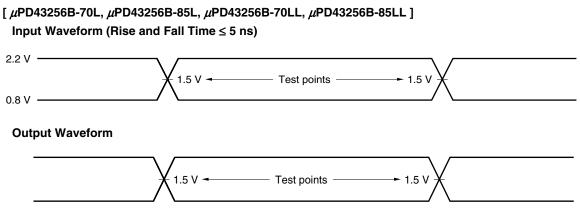
VI/O : Input / Output voltage

2. These DC characteristics are in common regardless of package types.

AC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

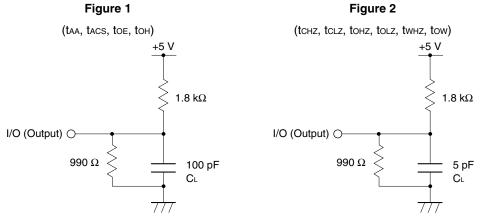
AC Test Conditions

NEC



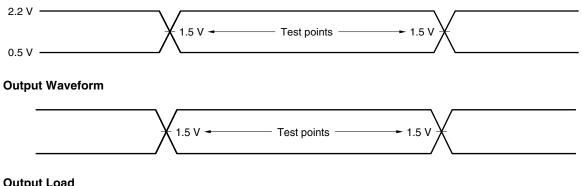
Output Load

AC characteristics should be measured with the following output load conditions.



Remark CL includes capacitance of the probe and jig, and stray capacitance.

[μPD43256B-A85, μPD43256B-A10, μPD43256B-A12, μPD43256B-B10, μPD43256B-B12, μPD43256B-B15] Input Waveform (Rise and Fall Time \leq 5 ns)



Output Load

AC characteristics should be measured with the following output load conditions.

taa, tacs, toe, toh	tchz, tclz, tohz, tolz, twhz, tow
1TTL + 100 pF	1TTL + 5 pF

Read Cycle (1/2)

Parameter	Symbol		Vcc ≥	4.5 V		Unit	Condition
		μPD432	256B-70	μPD432			
				μPD43256B-	A85/A10/A12		
				μPD43256B-	B10/B12/B15		
		MIN.	MAX.	MIN.	MAX.		
Read cycle time	trc	70		85		ns	
Address access time	taa		70		85	ns	Note
/CS access time	tacs		70		85	ns	
/OE access time	toe		35		40	ns	
Output hold from address change	tон	10		10		ns	
/CS to output in low impedance	tcLz	10		10		ns	
/OE to output in low impedance	tolz	5		5		ns	
/CS to output in high impedance	tснz		30		30	ns	
/OE to output in high impedance	tонz		30		30	ns	

Note See the output load.

Remark These AC characteristics are in common regardless of package types and L, LL versions.

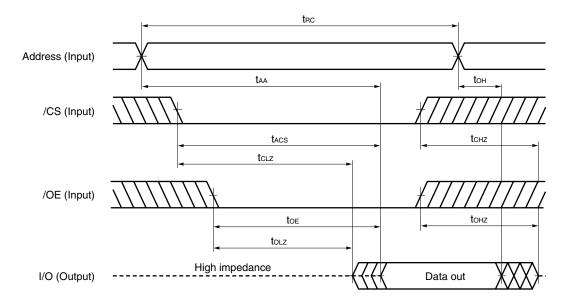
Read	Cycle	(2/2)
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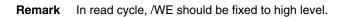
Parameter	Symbol			Vcc≥	3.0 V					Vcc ≥	2.7 V			Unit	Con-
		•	3256B .85		3256B 10	·	3256B 12		3256B 10		3256B 12		3256B 15		dition
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read cycle time	trc	85		100		120		100		120		150		ns	
Address access time	taa		85		100		120		100		120		150	ns	Note
/CS access time	tacs		85		100		120		100		120		150	ns	
/OE access time	toe		50		60		60		60		60		70	ns	
Output hold from address change	tон	10		10		10		10		10		10		ns	
/CS to output in low impedance	tcLz	10		10		10		10		10		10		ns	
/OE to output in low impedance	tolz	5		5		5		5		5		5		ns	
/CS to output in high impedance	tснz		35		35		40		35		40		50	ns	
/OE to output in high impedance	tонz		35		35		40		35		40		50	ns	

Note See the output load.

Remark These AC characteristics are in common regardless of package types.

Read Cycle Timing Chart





Write Cycle (1/2)

Parameter	Symbol		$V_{CC} \ge 4.5 V$						
		μPD432	256B-70	μPD432					
				μPD43256B-	A85/A10/A12				
				μPD43256B-	B10/B12/B15				
		MIN.	MAX.	MIN.	MAX.				
Write cycle time	twc	70		85		ns			
/CS to end of write	tcw	50		70		ns			
Address valid to end of write	taw	50		70		ns			
Write pulse width	twp	55		60		ns			
Data valid to end of write	tow	30		35		ns			
Data hold time	tон	0		0		ns			
Address setup time	tas	0		0		ns			
Write recovery time	twn	0		0		ns			
/WE to output in high impedance	twнz		30		30	ns	Note		
Output active from end of write	tow	10		10		ns			

Note See the output load.

Remark These AC characteristics are in common regardless of package types and L, LL versions.

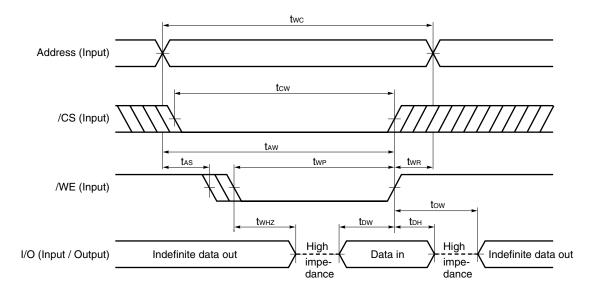
Write Cycle (2/2)

Parameter	Symbol			Vcc≥	3.0 V	_				Vcc ≥	2.7 V	_		Unit	Con-
		µPD4	3256B	µPD4	3256B	µPD4	3256B	µPD4	3256B	μPD4	3256B	μPD4	3256B		dition
		-A	85	-A	10	-A	12	-B	10	-B	12	-B	15		
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Write cycle time	twc	85		100		120		100		120		150		ns	
/CS to end of write	tcw	70		70		90		70		90		100		ns	
Address valid to end of write	taw	70		70		90		70		90		100		ns	
Write pulse width	twp	60		60		80		60		80		90		ns	
Data valid to end of write	tow	60		60		70		60		70		80		ns	
Data hold time	tон	0		0		0		0		0		0		ns	
Address setup	tas	0		0		0		0		0		0		ns	
Write recovery	twr	0		0		0		0		0		0		ns	
/WE to output in high impedance	twнz		30		35		40		35		40		50	ns	Note
Output active from end of write	tow	10		10		10		10		10		10		ns	

Note See the output load.

Remark These AC characteristics are in common regardless of package types.

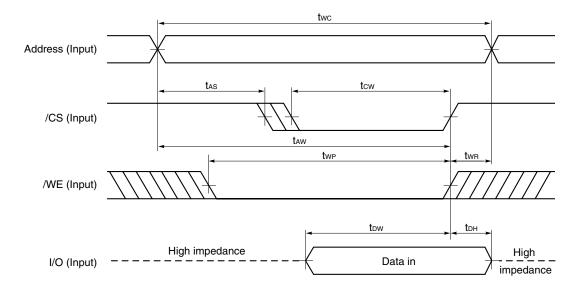
Write Cycle Timing Chart 1 (/WE Controlled)



Cautions 1. /CS or /WE should be fixed to high level during address transition.

- 2. When I/O pins are in the output state, therefore the input signals must not be applied to the output.
- Remarks 1. Write operation is done during the overlap time of a low level /CS and a low level /WE.
 - 2. When /WE is at low level, the I/O pins are always high impedance. When /WE is at high level, read operation is executed. Therefore /OE should be at high level to make the I/O pins high impedance.
 - **3.** If /CS changes to low level at the same time or after the change of /WE to low level, the I/O pins will remain high impedance state.

Write Cycle Timing Chart 2 (/CS Controlled)



- Cautions 1. /CS or /WE should be fixed to high level during address transition.
 - 2. When I/O pins are in the output state, therefore the input signals must not be applied to the output.

Remark Write operation is done during the overlap time of a low level /CS and a low level /WE.

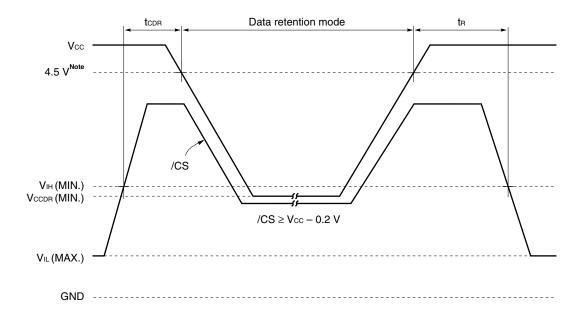
Low Vcc Data Retention Characteristics (T_A = 0 to 70 °C)

Parameter	Symbol Test Condition		μPE	043256B-	-xxL	μPD	Unit		
						μPE	043256B-	Axx	
						μPE	043256B	Bxx	
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
Data retention supply voltage	VCCDR	$/CS \ge V_{CC} - 0.2 V$	2.0		5.5	2.0		5.5	V
Data retention supply current	ICCDR	$Vcc = 3.0 \text{ V}, \ /CS \geq Vcc - 0.2 \text{ V}$		0.5	20 ^{Note1}		0.5	7 ^{Note2}	μA
Chip deselection to data retention mode	t CDR		0			0			ns
Operation recovery time	tR		5			5			ms

Notes 1. 3 μ A (T_A \leq 40 °C)

2. 2 μ A (T_A \leq 40 °C), 1 μ A (T_A \leq 25 °C)

Data Retention Timing Chart

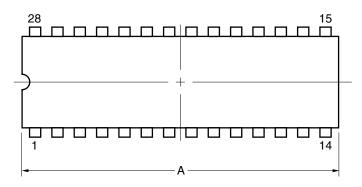


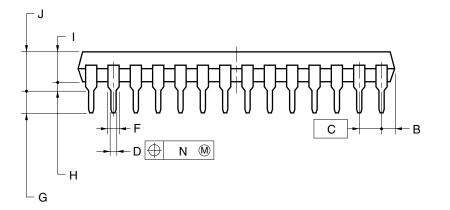
Note A version : 3.0 V, B version : 2.7 V

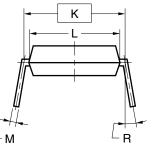
Remark The other pins (Address, /OE, /WE, I/O) can be in high impedance state.

Package Drawings

28-PIN PLASTIC DIP (15.24 mm (600))





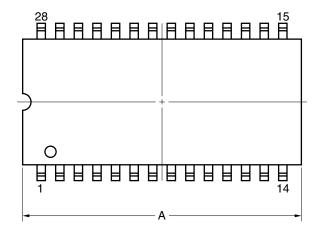


NOTES

- 1. Each lead centerline is located within 0.25 mm of its true position (T.P.) at maximum material condition.
- 2. Item "K" to center of leads when formed parallel.

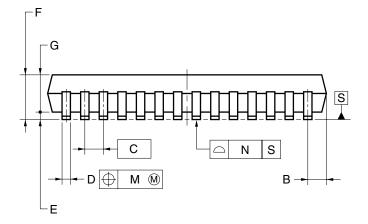
ITEM	MILLIMETERS
А	38.10 MAX.
В	2.54 MAX.
С	2.54 (T.P.)
D	0.50±0.10
F	1.2 MIN.
G	3.6±0.3
Н	0.51 MIN.
I	4.31 MAX.
J	5.72 MAX.
К	15.24 (T.P.)
L	13.2
М	$0.25^{+0.10}_{-0.05}$
N	0.25
R	0 - 15°
F	P28C-100-600A1-2

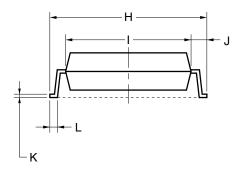
28-PIN PLASTIC SOP (11.43 mm (450))



detail of lead end







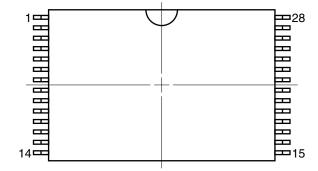
ΝΟΤΕ

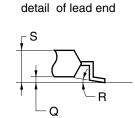
Each lead centerline is located within 0.12 mm of its true position (T.P.) at maximum material condition.

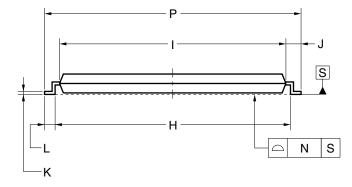
ITEM	MILLIMETERS
А	$18.0\substack{+0.6\\-0.05}$
В	1.27 MAX.
С	1.27 (T.P.)
D	$0.42\substack{+0.08\\-0.07}$
E	0.2±0.1
F	2.95 MAX.
G	2.55±0.1
Н	11.8±0.3
I	8.4±0.1
J	1.7±0.2
К	0.22±0.05
L	0.7±0.2
М	0.12
Ν	0.10
Р	$3^{\circ}^{+7^{\circ}}_{-3^{\circ}}$

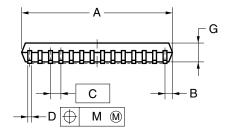
P28GU-50-450A-4

28-PIN PLASTIC TSOP(I) (8x13.4)







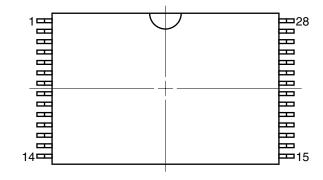


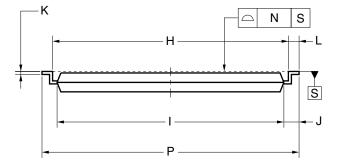
NOTES

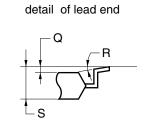
- 1. Each lead centerline is located within 0.08 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash : 8.4mm MAX.)

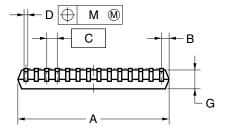
ITEM	MILLIMETERS
А	8.0±0.1
В	0.6 MAX.
С	0.55 (T.P.)
D	$0.22\substack{+0.08 \\ -0.07}$
G	1.0
Н	12.4±0.2
I	11.8±0.1
J	0.8±0.2
к	$0.145\substack{+0.025\\-0.015}$
L	0.5±0.1
М	0.08
Ν	0.10
Р	13.4±0.2
Q	0.1±0.05
R	$3^{\circ}^{+7^{\circ}}_{-3^{\circ}}$
S	1.2 MAX.
	P28GW-55-9JL-2

28-PIN PLASTIC TSOP(I) (8x13.4)









NOTE

- 1. Each lead centerline is located within 0.08 mm of its true position (T.P.) at maximum material condition.
- 2. "A" excludes mold flash. (Includes mold flash : 8.4mm MAX.)

ITEM	MILLIMETERS
A	8.0±0.1
В	0.6 MAX.
С	0.55 (T.P.)
D	$0.22\substack{+0.08\\-0.07}$
G	1.0
Н	12.4±0.2
I	11.8±0.1
J	0.8±0.2
к	$0.145\substack{+0.025\\-0.015}$
L	0.5±0.1
М	0.08
N	0.10
Р	13.4±0.2
Q	0.1±0.05
R	$3^{\circ}^{+7^{\circ}}_{-3^{\circ}}$
S	1.2 MAX.
	P28GW-55-9KL-2

Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the μ PD43256B.

Types of Surface Mount Device

μPD43256BGU-xxL	: 28-pin PLASTIC SOP (11.43 mm (450))
μ PD43256BGU-xxLL	: 28-pin PLASTIC SOP (11.43 mm (450))
μ PD43256BGU-Axx	: 28-pin PLASTIC SOP (11.43 mm (450))
μPD43256BGU-Bxx	: 28-pin PLASTIC SOP (11.43 mm (450))
μPD43256BGW-xxLL-9JL	: 28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)
μ PD43256BGW-xxLL-9KL	: 28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)
μPD43256BGW-Axx-9JL	: 28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)
μPD43256BGW-Axx-9KL	: 28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)
μPD43256BGW-Bxx-9JL	: 28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)
µPD43256BGW-Bxx-9KL	: 28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)
μPD43256BGU-xxL-A	: 28-pin PLASTIC SOP (11.43 mm (450))
μPD43256BGU-xxLL-A	: 28-pin PLASTIC SOP (11.43 mm (450))
μPD43256BGU-Axx-A	: 28-pin PLASTIC SOP (11.43 mm (450))
μPD43256BGU-Bxx-A	: 28-pin PLASTIC SOP (11.43 mm (450))
µPD43256BGW-xxLL-9JL-A	: 28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)
µPD43256BGW-xxLL-9KL-A	: 28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)
μPD43256BGW-Axx-9JL-A	: 28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)
μPD43256BGW-Axx-9KL-A	: 28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)
μPD43256BGW-Bxx-9JL-A	: 28-pin PLASTIC TSOP (I) (8x13.4) (Normal bent)
μ PD43256BGW-Bxx-9KL-A	: 28-pin PLASTIC TSOP (I) (8x13.4) (Reverse bent)

Types of Through Hole Mount Device

μPD43256BCZ-xxL : 28-pin PLASTIC DIP (15.24 mm (600)) μPD43256BCZ-xxLL : 28-pin PLASTIC DIP (15.24 mm (600))

Soldering process	Soldering conditions	
Wave soldering (only to leads)	Solder temperature : 260 °C or below,	
	Flow time : 10 seconds or below	
Partial heating method	Terminal temperature : 300 °C or below,	
	Time : 3 seconds or below (Per one lead)	

Caution Do not jet molten solder on the surface of package.

Revision History

Edition/	Page		Type of	Location	Description
Date	This	Previous	revision		(Previous edition \rightarrow This edition)
	edition	edition			
14th edition/	p.1	p.1	Deletion	-	Description of Version X and P has been deleted.
Jun. 2006					

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[MEMO]

NOTES FOR CMOS DEVICES —

1 VOLTAGE APPLICATION WAVEFORM AT INPUT PIN

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (MAX) and V_{IH} (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (MAX) and V_{IH} (MIN).

② HANDLING OF UNUSED INPUT PINS

Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.

③ PRECAUTION AGAINST ESD

A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must have hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.

④ STATUS BEFORE INITIALIZATION

Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.

5 POWER ON/OFF SEQUENCE

In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current.

The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.

6 INPUT OF SIGNAL DURING POWER OFF STATE

Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

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- "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support).
- "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

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